

Notice of References Cited	Application/Control No. 10/782,660	Applicant(s)/Patent Under Reexamination LAI ET AL.	
	Examiner Thinh T. Nguyen	Art Unit 2818	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,208,023	03-2001	Nakayama et al.	257/696
	B	US-6,853,059	02-2005	Jang, Sung Sik	257/675
	C	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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